TOSHIBA 2SC5323

TENTATIVE

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 3 2 3

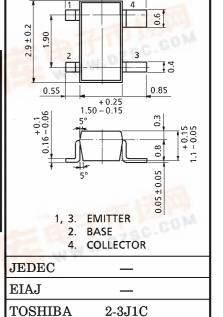
VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

 $: NF = 1.4 \, dB \, (f = 2 \, GHz)$ Low Noise Figure High Gain : Ga = 12 dB (f = 2 GHz)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	V _{CBO}	8	V
Collector-Emitter Voltage	VCEO	5	V
Emitter-Base Voltage	VEBO	1.5	V
Collector Current	$I_{\mathbf{C}}$	10	mA
Base Current	$I_{\mathbf{B}}$	5	mA
Collector Power Dissipation	PC	150	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	°C

MARKING

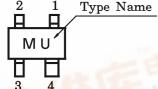


+ 0.2 2.9 - 0.3

Unit in mm

Weight: 0.012 g

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MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	$ m f_{T}$	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}$	13	16	150.0	GHz
Incortion (-ain	$ S_{21e} ^2(1)$	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}, f = 1 \text{ GHz}$	14.5	17.5	_	- dB
	$ S_{21e} ^2$ (2)	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}, f = 2 \text{ GHz}$	9	12	_	
Noise Figure	NF (1)	$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ mA}, f = 1 \text{ GHz}$	_	0.9	1.8	dB
	NF (2)	$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ mA}, f = 2 \text{ GHz}$	_	1.4	2.3	ub

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB} = 8 V, I_{E} = 0$	_	-	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB} = 1 \text{ V}, I_{C} = 0$		4-11	10	μ A
DC Current Gain	$h_{ ext{FE}}$	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}$	50	An D.	250	V
Output Capacitance	C_{ob}	$V_{CB} = 2.5 \text{ V}, I_{E} = 0,$		0.4	_	pF
Reverse Transfer Capacitance	C_{re}	f = 1 MHz (Note)	_	0.3	0.7	pF

(Note): Cre is measured by 3 terminal method with Capacitance Bridge. **CAUTION**

This device electrostatic sensitivity. Please handle with caution.

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